Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/577,854	TAKEI ET AL.	
Examiner	Art Unit	
Sin J. Lee	1795	

SEARCHED					
Class	Subclass	Date	Examiner		

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
DATE	EXMR			
11/15/2009	SJL			
11/15/2009	SJL			
	DATE 11/15/2009			